

RECEIVED

~~JUL 10 2003~~

Technology Center 2100

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

<div>LIST OF PRIOR ART CITED BY APPLICANT</div> <div>(PTO-1449)</div> <div><div>OTPF</div><div>JUL 08 2003</div><div>3034</div><div>PATENT & TRADEMARK OFFICE</div></div>				ATTY. DOCKET NO. CIT/K-108		APPLN. SERIAL NO. 09/495,250	
				APPLICANT(S) Jin Soo LEE and Hyeon Jun KIM			
				FILING DATE January 31, 2000		GROUP 2172	
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE	
U.S. PATENT APPLICATION PUBLICATIONS							
	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS		
U.S. PATENT APPLICATIONS							
	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS		
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
h	08-313615 •	06/09/1998	Japan			Abst.	
h	07-260148 •	04/15/1997	Japan			Abst.	
u	07-055937 •	09/27/1996	Japan			Abst.	
h	07-055935 •	09/27/1996	Japan			Abst.	
u	06-028059 •	09/12/1995	Japan			Abst.	
OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)							
EXAMINER				DATE CONSIDERED	Technology Center 2100		

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

<div>LIST OF PRIOR ART CITED BY APPLICANT</div> <div>PTO-1449)</div> <div><div>OFFICE OF PATENT & TRADEMARK JUL 08 2003</div></div>				ATTY. DOCKET NO. CIT/K-108		APPLN. SERIAL NO. 09/495,250	
				APPLICANT(S) Jin Soo LEE and Hyeon Jun KIM			
				FILING DATE January 31, 2000		GROUP 2172	
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE	
U.S. PATENT APPLICATION PUBLICATIONS							
	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS		
U.S. PATENT APPLICATIONS							
	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS		
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
W	05-309135	06/23/1995	Japan			Abst.	
W	05-145289	01/24/1995	Japan			Abst.	
W	04-320665	06/14/1994	Japan			Abst.	
OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)							
EXAMINER				DATE CONSIDERED			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.